Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2	("6690546").PN.	USPAT; USOCR; JPO; DERWENT	OR	OFF	2005/07/21 09:18
L2	3	("5422764" | "5864446" | "6173485").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/07/21 09:19
L3	5	("3563443" | "4799119" | "5687479" | "5859749" | "5870258").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/07/21 09:20
L4	289	29/603.03,603.05,603.06.ccls.	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:22
L5	963	29/593,603.09.ccls.	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:22
L6	1233	4 or 5	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:23
L7	210	360/244.1,244.2,245.8.ccls.	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:24
L8	2420	test$3 with probe with terminal	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:35
L9	3	7 and 8	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:25
L10	11	5 and 8	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:28
L11	5	("3563443" | "4799119" | "5687479" | "5859749" | "5870258").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/07/21 09:27
L12	9	10 and @ad<"20000427"	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:28
L13	308	324/210.ccls.	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:32
L14	4	8 and 13	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:32

L15	22	(("6202288") or ("6134084") or ("6351347") or ("6369985") or ("6084746") or ("6388840") or ("6181520") or ("6266213") or ("6339519") or ("5422764") or ("5864446") or ("6173485")).PN.	USPAT; USOCR; JPO; DERWENT	OR	OFF	2005/07/21 09:34
L16	1	8 and 15	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:34
L17	13	15 and IC	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:35
L18	39305	test$3 with probe	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:35
L19	1	17 and 18	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:45
L20	3	15 and test$3	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:37
L21	4	Gouo-akio.in.	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:36
L22	1	21 and test$3	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:37
L23	1	21 and probe	USPAT; JPO; DERWENT	OR	ON	2005/07/21 09:37

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☐   **1. Monolithic integrated circuits for mm-wave instrumentation**
Marsland, R.A.; Madden, C.J.; Van Der Weide, D.W.; Shakouri, M.S.; Bloom, [
Gallium Arsenide Integrated Circuit (GaAs IC) Symposium, 1990. Technical Di
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7-10 Oct. 1990 Page(s):19 - 22
Digital Object Identifier 10.1109/GAAS.1990.175436

AbstractPlus | Full Text: PDF(240 KB)   IEEE CNF

☐   **2. Monolithic sampling head IC**
Miura, A.; Yakihara, T.; Uchida, S.; Oka, S.; Kobayashi, S.; Kamada, H.; Doba
Microwave Theory and Techniques, IEEE Transactions on
Volume 38, Issue 12, Dec 1990 Page(s):1980 - 1985
Digital Object Identifier 10.1109/22.64583

AbstractPlus | Full Text: PDF(492 KB)   IEEE JNL

☐   **3. 100 GHz GaAs MMIC sampling head**
Marsland, R.A.; Valdivia, V.; Madden, C.J.; Rodwell, M.J.W.; Bloom, D.M.;
Electron Devices Meeting, 1988. Technical Digest., International
11-14 Dec. 1988 Page(s):897 - 899
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8-10 May 1990 Page(s):845 - 848 vol.2
Digital Object Identifier 10.1109/MWSYM.1990.99711

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